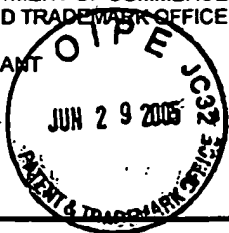



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U.S. PATENT DOCUMENTS							
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
DS	AA	6,013,583	01/2000	Ajmera et al.	—	—	—
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

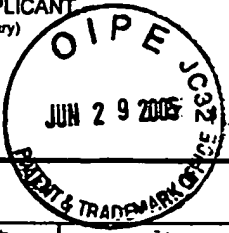
FOREIGN PATENT DOCUMENTS								
Examiner's Initials	Class	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
DS	AJ	0817251 A1	11.06.97	EPO (IBM)				
D	AK	US2004/021156	07.07.03	PCT (Micron – Internat'l Search Rep.)				
	AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
DS	AM	Chen et al., <i>Excimer Laser-Induced Ti Silicidation to Eliminate the Fine-Line Effect for Integrated Circuit Device Fabrication</i> , J. ELECTROCHEM. SOC., Vol. 149, No. 11, pp. G609-G612 (2002).
↓	AN	Nishiyama et al., <i>Agglomeration Resistant Self-Aligned Silicide Process Using N₂ Implantation Into TiSi₂</i> , JPN. J. APPL. PHYS., Vol. 36, Pt. 1, No. 6A, pp. 3639-3643 (June 1997).
↓	AO	Wolf, <i>Chapter 13: Polycides and Salicides of TiSix, CoSi₂, and NiSi</i> , SILICON PROCESSING FOR THE VLSI ERA, Vol. IV, pp. 603-604 (pre-2003).

EXAMINER	DATE CONSIDERED
	 7/19/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS							
Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
<div style="font-size: 2em;">DS</div> <div style="font-size: 4em;">↓</div>	AA	2001/0041250 A1	11/2001	Werkhoven et al.			
	AB	2002/0000195 A1	01/2002	Bang et al.			
	AC	2002/0018849 A1	02/2002	George et al.			
	AD	2003/0032281 A1	02/2003	Werkhoven et al.			
	AE	2003/0129826 A1	07/2003	Werkhoven et al.			
	AF	2004/0209484 A1	10/2004	Hill et al.			
	AG	2004/0266153 A1	12/2004	Hu			
AH							
AI							

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AJ							
AK							
AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AM		
	AN		
	AO		

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